



Docket No.: M4065.0468/P468  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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In re Patent Application of:  
Phillip E. Byrd, et al.

Application No.: 09/941,761

Allowed: May 20, 2003

Filed: August 30, 2001

Group Art Unit: 2812

For: STRUCTURE FOR TEMPORARILY  
ISOLATING A DIE FROM A  
COMMON CONDUCTOR TO  
FACILITATE WAFER LEVEL  
TESTING (AS AMENDED)

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Examiner: A. Stevenson

**COMMENTS ON EXAMINER'S STATEMENT  
OF REASONS FOR ALLOWANCE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Applicant has reviewed the Examiner's Reasons for Allowance, mailed on May 20, 2003 (part of Paper No. 11). The Examiner provided reasons for allowance with respect to claims 1 and 42.

Applicant note that the allowed claims define over the prior art for many different reasons. The reasons stated in the Examiner's Statement of Reasons for Allowance should be interpreted as highlighting only one of the many differences between prior art and the claimed invention.

Otherwise, Applicant agrees with the Examiner that the claimed invention is not described or suggested in the prior art.

Dated: August 20, 2003

Respectfully submitted,

By  \_\_\_\_\_

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